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Indian Standard



SPECIFICATION FOR QUARTZ CRYSTAL UNITS USED FOR FREQUENCY CONTROL AND SELECTION

PART 4 SERIES AB FOR OSCILLATORS

Section 2 Quartz Crystal Unit Type AB-02

- **0. General** This standard shall be read in conjunction with IS:8271 (Part 1) 1981 'Specification for quartz crystal units used for frequency control and selection: Part 1 General requirements and tests (first revision)'.
- 1. Outline and Dimensions Holder outline shall conform to Type AB (see Sheet 1A of IS: 4570 1968 'Specification for crystal holders').
- 2. Marking See 8 of IS: 8271 (Part 1) 1981.
- 3. Construction and Workmanship See 7 of IS: 8271 (Part 1) 1981.
- 4. Test Schedule and Detail Requirements
- 4.1 General Conditions for Test See 9.2 of IS: 8271 (Part 1) 1981.
- 4.2 Test Schedule The sequence and grouping of type, routine and acceptance tests shall be in accordance with 9.1 of IS:8271 (Part 1) 1981.
- 4.3 Detail Requirements The detail requirements applicable to this particular type of crystal unit shall be as specified in Table 1.

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TABLE 1 DETAIL REQUIREMENTS OF QUARTZ CRYSTAL UNIT TYPE AB-02 (Clause 4.3)

SI No.	Characteristic	Requirement		
(1)	(2)	(3)		
i)	Type of holder	AB (see 1)		
ii)	Frequency range	16 to 100 kHz		
lii)	Frequency tolerance: Operating temperature range	±120 ppm		
iv)	Resonance resistance	See Table 2		
v)	Mode of oscillation	Fundamental		
vi)	Load capacitance	Infinity		
vii)	Capacitance shunt	See Table 3		
viii)	Operating temperature range	-40°C to +70°C		
ix)	Test set, calibration values and rated drive level	See Table 4		
x)	Shock [in accordance with 9.15 (Severity A) of 1S: 8271 (Part 1) - 1981]:			
	a) Frequency change permitted	±10 ppm		
	b) Resonance resistance change permitted	土15 percent		
xi)	Vibration [in accordance with 9.16.1 (Severity A) of IS: 8271 (Part 1) - 1981]:			
	a) Frequency change permitted	±10 ppm		
	b) Resonance resistance change permitted ±15 perc			
xii)	Temperature cycling:			
	a) Frequency change permitted	±10 ppm		
	b) Resonance resistance change permitted	±15 percent		
xiii)	Temperature run:			
	a) Frequency change permitted	\pm 10 ppm		
	b) Resonance resistance change permitted	±15 percent		
xiv)	Bond strength	From 16 to 60 kHz 8 N (<i>Min</i>), and over 60 to 100 kHz 7 N (<i>Min</i>)		

TABLE 2 RESONANCE RESISTANCE

[Table 1 (iv)]

Frequency Range	Maximum Resonance Resistance
(1)	(2)
kHz	Ohms
From 16 to 30	100 000
Over 30 to 50	90 000
,, 50 ,, 70	80 000
,, 70 ,, 90	70 000
,, 80 ,, 100	60 000

TABLE 3 CAPACITANCE SHUNT

[Table 1 (vii)]

Frequency Range

(1)

(2)

kHz

From 16 to 34

Over 34 to 54 $\frac{33}{\sqrt{f}} + 1.6$ $\frac{24}{\sqrt{f}} + 1.6$

TABLE 4 TEST SET, CALIBRATION VALUES AND RATED DRIVE LEVEL

[Table 1 (ix)]

SI No.	Frequency Range	Calibration Value		Rated Drive	Test Set
		Resistance	Resistor Voltage Drop	Level	Set
(1)	(2)	(3)	(4)	(5)	(6)
	kKz	Ohms	Volts	mW	
i)	From 16 to 30	7 0 00 0	2.65	0.1	
ii)	Over 30 ,, 50	63 000	2.51	0.1	TS-
iii)	,, 50 ,, 70	56 000	2:37	0.1	710/TSM
iv)	,, 70 ,, 90	49 000	2:21	0.1	
v)	,, 90 ,, 100	42 00 0	2.05	ر 0·1 ک	

EXPLANATORY NOTE

This standard (Part 4/Sec 2) covers the requirements of crystal unit, style QC-02 of JSS 50901 (1971) 'Detail specification for crystal unit, quartz, styles QC-01 and QC-02', issued by the Directorate of Standardization, Ministry of Defence, Government of India.

^{*}Capacitance determined by formulae given is subject to a tolerance of \pm 15 percent. The letter 'f' represents specified frequency in kHz.